

ABSTRACT

A testing apparatus, by which an optical system to
5 irradiate a test light to a solid-state imaging device is
easily aligned with the solid-state imaging device and
highly efficient tests can be conducted, is provided.

It includes an optical module 35 for irradiating a
light from a light source to a light receiving surface of
10 the solid-state imaging device through a pin hole, a
probe card 20 having contact probes for contacting pads
of the solid-state imaging device, and a motor 30 and a
holding arm 31 for moving the optical module 35 to a
predetermined position corresponding to the solid-state
15 imaging device to be tested through an opening 20h
provided to the probe card 20 in a state where the
contact probes 21 contact the pads of the solid-state
imaging device to be tested.